

IRF9Z14LPBF-VB Datasheet

P-Channel 60-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^a	Q _g (Typ.)			
- 60	0.0160at V _{GS} = - 10 V	- 53	76 nC			
- 60	0.0200 at V _{GS} = - 4.5 V	- 42	70110			

FEATURES

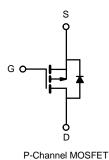
- Trench Power MOSFET
- 100 % UIS Tested

APPLICATIONS

Load Switch







Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	- 60	V		
Gate-Source Voltage	V_{GS}	± 20			
	T _C = 25 °C		- 53 ^a		
Continuous Proin Current (T. – 150 °C)	T _C = 70 °C		- 46.8		
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	I _D	9.2 ^b		
	T _A = 70 °C		- 8.1 ^b	A	
Pulsed Drain Current	I _{DM}	- 150			
Avalanche Current Pulse		I _{AS}	- 45		
Single Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	101	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C	1	69 ^a	^	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	2.1 ^b	A	
	T _C = 25 °C		104.2 ^a		
Manianum Danian Dinain ation	T _C = 70 °C	В	66.7 ^a	14/	
Maximum Power Dissipation	T _A = 25 °C	P _D	3.1 ^b	W	
	T _A = 70 °C		2 ^b		
Operating Junction and Storage Temperature R	T _J , T _{stg}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^b	Steady State	R_{thJA}	33	40	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.98	1.2]	

Notes:

- a. Based on T_C = 25 °C.
- b. Surface mounted on 1" x 1" FR4 board.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 60			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	T _J I _D = - 250 μA		68		\//90
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	1 _D = - 250 μΑ		- 5.2		mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	- 1		- 3	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zana Oata Valta na Busin Oannant		V _{DS} = - 60 V, V _{GS} = 0 V			- 1	^
Zero Gate Voltage Drain Current	IDSS	V _{DS} = - 60 V, V _{GS} = 0 V, T _J = 55 °C			- 10	μA
On-State Drain Current ^a	I _{D(on)}	V _{DS} = - 5 V, V _{GS} = - 10 V	- 120			Α
	В	V _{GS} = - 10 V, I _D = - 30 A	0.0160			
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 20 A		0.0200	0200	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 50 A	20			S
Dynamic ^b						l
Input Capacitance	C _{iss}			3500		pF
Output Capacitance	C _{oss}	V _{DS} = - 25 V, V _{GS} = 0 V, f = 1 MHz		390		
Reverse Transfer Capacitance	C _{rss}			290		
Total Cata Chausa	Qg	V _{DS} = - 30 V, V _{GS} = - 10 V, I _D = - 55 A		76 115		
Total Gate Charge				38	60	nC
Gate-Source Charge	Q_{gs}	$V_{DS} = -30 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -55 \text{ A}$		16		
Gate-Drain Charge	Q_{gd}			19		
Gate Resistance	R _g	f = 1 MHz		5.2		Ω
Turn-On Delay Time	t _{d(on)}			10	15	
Rise Time	t _r	$V_{DD} = -2 \text{ V}, R_L = 2 \Omega$		7	15	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 10 A, V_{GEN} = - 10 V, R_g = 1 Ω		70	110	ns ns
Fall Time	t _f			40	60	
Drain-Source Body Diode Characteristic	s					l
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			- 69	
Pulse Diode Forward Current ^a	I _{SM}				- 150	A
Body Diode Voltage	V _{SD}	I _S = - 30 A		- 1	- 1.5	V
Body Diode Reverse Recovery Time	t _{rr}			45	68	ns
Body Diode Reverse Recovery Charge Q _{rr}		1		59	120	nC
Reverse Recovery Fall Time	t _a	$I_F = -50 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 °C$		29		
Reverse Recovery Rise Time	t _b	_		16		ns

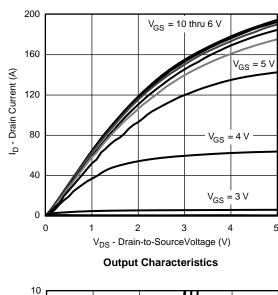
Notes:

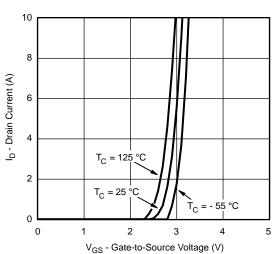
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

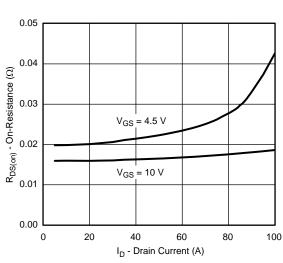


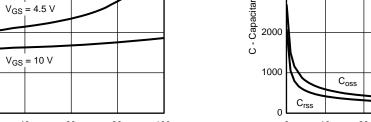
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

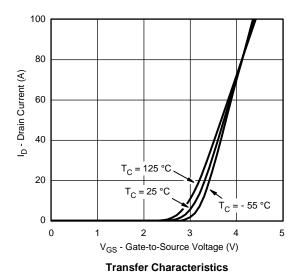


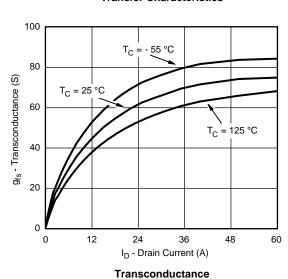


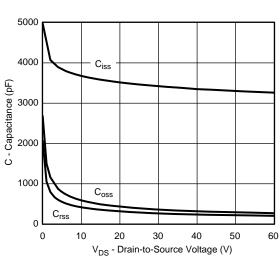
Transfer Characteristics







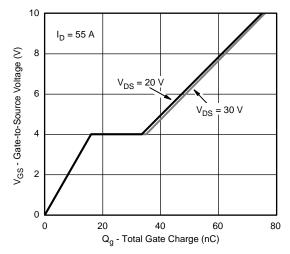




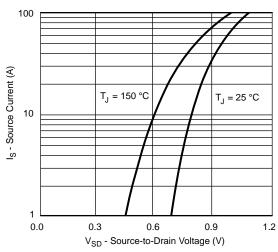
On-Resistance vs. Drain Current Capacitance



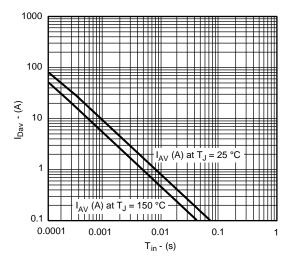
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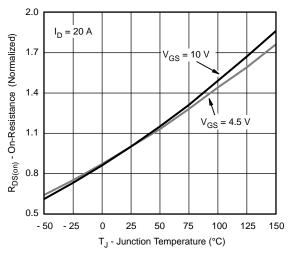
Gate Charge



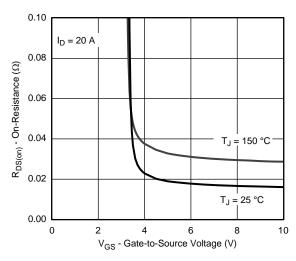
Source-Drain Diode Forward Voltage



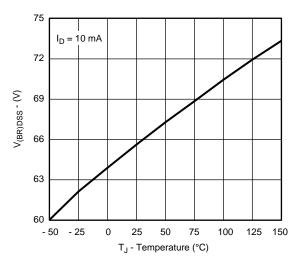
Single Pulse Avalanche Current Capability vs. Time



On-Resistance vs. Gate-to-Source Voltage



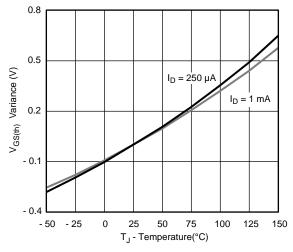
On-Resistance vs. Gate-to-Source Voltage

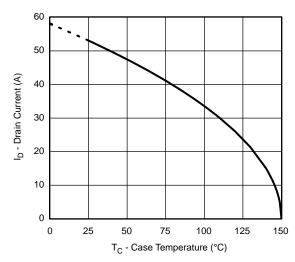


Drain-Source Breakdown Voltage vs. Junction Temperature

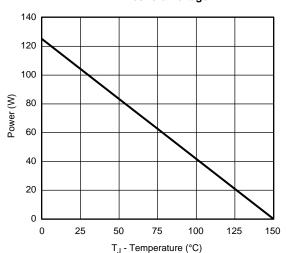


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

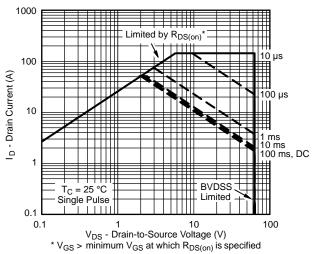




Threshold Voltage

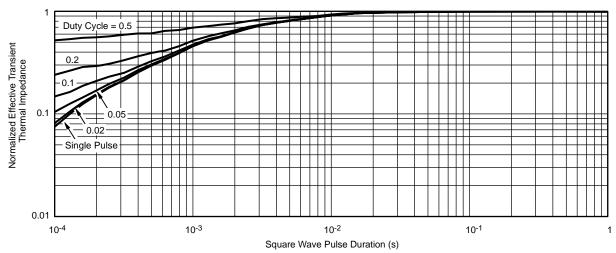


Max. Drain Current vs. Case Temperature



Power Derating, Junction-to-Case

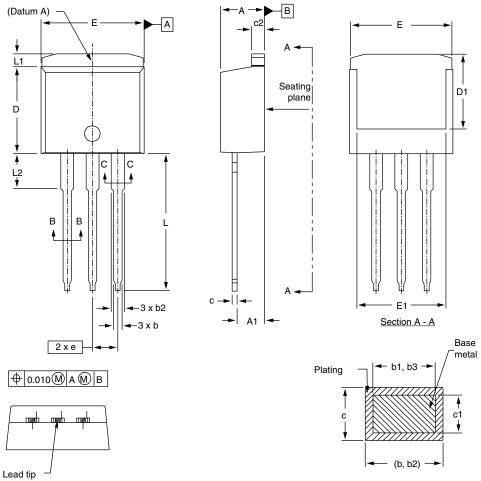




Normalized Thermal Transient Impedance, Junction-to-Case



I²PAK (TO-262) (HIGH VOLTAGE)



INCHES MILLIMETERS DIM. MIN. MAX. MIN. MAX. 4.06 0.190 Α 4.83 0.160 Α1 2.03 3.02 0.080 0.119 b 0.51 0.99 0.020 0.039 b1 0.51 0.89 0.020 0.035 b2 1.14 1.78 0.045 0.070 b3 1.14 1.73 0.045 0.068 0.38 0.74 0.015 0.029 С с1 0.38 0.58 0.015 0.023 c2 1.14 1.65 0.045 0.065

	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
D	8.38	9.65	0.330	0.380
D1	6.86	-	0.270	-
E	9.65	10.67	0.380	0.420
E1	6.22	-	0.245	-
е	2.54 BSC		0.100 BSC	
L	13.46	14.10	0.530	0.555
L1	-	1.65	-	0.065
L2	3.56	3.71	0.140	0.146

Section B - B and C - C Scale: None

ECN: S-82442-Rev. A, 27-Oct-08

DWG: 5977

Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm per side. These dimensions are measured at the outmost extremes of the plastic body.
- 3. Thermal pad contour optional within dimension E, L1, D1, and E1.
- 4. Dimension b1 and c1 apply to base metal only.



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